Samaneh Ranjbar <sup>1,4,5\*</sup>, Guy Brammertz <sup>2,3</sup>, Bart Vermang <sup>2,3,4</sup>, Afshin Hadipour <sup>4</sup>, M. Sylvester <sup>2,4,5</sup>, Aniket Mule<sup>4,5,6</sup>, Marc Meuris <sup>2,3</sup>, A. F. da Cunha<sup>1</sup> and Jef Poortmans <sup>3,4,5</sup>

<sup>1</sup> I3N - Departamento de Física, Universidade de Aveiro, Campus Universitário de Santiago, 3810-193 Aveiro, Portugal.

<sup>2</sup> imec division IMOMEC - partner in Solliance, Wetenschapspark 1, 3590 Diepenbeek, Belgium
 <sup>3</sup> Institute for Material Research (IMO) Hasselt University, Wetenschapspark 1, 3590
 Diepenbeek, Belgium

<sup>4</sup> imec- partner in Solliance, Kapeldreef 75, 3001 Leuven, Belgium

<sup>5</sup> Department of Electrical Engineering (ESAT), KU Leuven, Kasteelpark Arenberg 10, 3001 Heverlee, Belgium

<sup>6</sup> Department of Mechanical and Process Engineering (D-MAVT), ETH Zurich, LEE K, Leonhardstrasse 21, 8092 Zurich, Switzerland

On the effect of absorber thickness in kesterite thin film solar cells

Key: RCJI6

<sup>\*</sup> Corresponding author; Tel: <u>+351 234370818</u>; E-mail: <u>samaneh.ranjbar@ua.pt</u>

Effect of Sn/Zn/Cu precursor stack thickness on two-step processed kesterite solar cell

Samaneh Ranjbar <sup>1,4,5\*</sup>, Guy Brammertz <sup>2,3</sup>, Bart Vermang <sup>2,3,4</sup>, Afshin Hadipour <sup>4</sup>, M. Sylvester <sup>2,4,5</sup>, Aniket Mule<sup>4,5,6</sup>, Marc Meuris <sup>2,3</sup>, A. F. da Cunha<sup>1</sup> and Jef Poortmans <sup>3,4,5</sup>

<sup>1</sup> I3N - Departamento de Física, Universidade de Aveiro, Campus Universitário de Santiago, 3810-193 Aveiro, Portugal.

<sup>2</sup> imec division IMOMEC - partner in Solliance, Wetenschapspark 1, 3590 Diepenbeek, Belgium

<sup>3</sup> Institute for Material Research (IMO) Hasselt University, Wetenschapspark 1, 3590 Diepenbeek, Belgium

<sup>4</sup> imec- partner in Solliance, Kapeldreef 75, 3001 Leuven, Belgium

<sup>5</sup> Department of Electrical Engineering (ESAT), KU Leuven, Kasteelpark Arenberg 10, 3001 Heverlee, Belgium

<sup>6</sup> Department of Mechanical and Process Engineering (D-MAVT), ETH Zurich, LEE K, Leonhardstrasse 21, 8092 Zurich, Switzerland

# Abstract

We have fabricated  $Cu_2ZnSnSe_4$  (CZTSe) solar cells with different absorber layer thickness. Absorber layers with different thickness were fabricated by changing the thickness of e-beam evaporated Sn/Zn/Cu precursor stacks and then selenization in a rapid thermal processing system.

<sup>\*</sup> Corresponding author; Tel: <u>+351 234370818</u>; E-mail: <u>samaneh.ranjbar@ua.pt</u>

Scanning electron microscopy revealed that by increasing the thickness the morphology of CZTSe films improves substantially and energy dispersive spectrometry measurements showed that the Cu to Sn ratio increased with increasing film thickness, despite a similar Cu to Sn ratio in the starting layers. A longer minority carrier lifetime and higher open circuit voltage were achieved for solar cells with thicker absorber layers. A maximum conversion efficiency of 7.8 % (without anti reflection coating) was achieved for a solar cell with 1.7  $\mu$ m thickness in which a low doping density of the order of 10<sup>15</sup> cm<sup>-3</sup> was measured, leading to a wide space charge region of about 300 nm

#### **Keywords:**

Kesterite solar cell, CZTSe, Sn/Zn/Cu precursor thickness, Absorber layer thickness

### 1. Introduction

Kesterite compound  $Cu_2ZnSn(S,Se)_4$ , CZTSSe is being investigated as a promising candidate for cost effective thin film solar cells. In addition of desirable photovoltaic properties such as high absorption coefficient ( > 10<sup>4</sup> cm<sup>-1</sup> ) and optimal band gap ( 1 - 1.5 eV depending on the S/Se composition ratio), CZTSSe consists of inexpensive and abundant elements [1]. So far 12.6 % conversion efficiency has been achieved for a CZTSSe solar cell synthesized by a hydrazine solution based process [2]. The effect of variation of thickness of absorber layer has been studied for pure sulfide  $Cu_2ZnSnS_4$  [3]. In this study we fabricated  $Cu_2ZnSnSe_4$  (CZTSe) solar cells by selenization of e-beam evaporated Sn, Zn and Cu layers. In order to fabricate CZTSe absorber layers with different thickness the thickness of Sn/Zn/Cu precursor stacks was changed. The effect of variation of the thickness on physical, optical and electrical properties of the solar cells is investigated.

## 2. Experimental details

Pure Cu<sub>2</sub>ZnSnSe<sub>4</sub> (CZTSSe) absorber layers were synthesized in a two-step process. First, Sn, Zn and Cu were subsequently deposited on Mo-coated Soda Lime Glass, (SLG) by e-beam evaporation. Metallic layers with different thickness (See Table.1) were deposited while the metallic ratios were kept constant in order to control the composition. In the second step, the Sn/Zn/Cu stacks were selenized by 10% H<sub>2</sub>Se gas diluted in N<sub>2</sub> for 15 min at 460 °C in a rapid thermal processing system with 1 °C/s heating rate. This selenization process has been already optimized and applied for sputtered Cu<sub>10</sub>Sn<sub>90</sub>/Zn/Cu stack layers [4]. Absorber layers with thicknesses of ~ 300, 700, 1000, 1200 and 1700 nm were fabricated. These absorber layers were etched in 5 % KCN solution for 2 min to remove the secondary phases from the surface. Solar cells were then completed by successive chemical bath deposition of CdS (~ 50 nm ), sputtering of intrinsic ZnO (~ 50 nm ) and Al-doped ZnO (~ 300-400 nm ) and finally evaporation of Ni/Al grids. Solar cells with 0.5 cm<sup>2</sup> area were isolated by needle scribing of the devices. Scanning electron microscopy (SEM) and energy dispersive spectrometry (EDS) of the absorbers were acquired by SU-70 Hitachi combined with a Rontec EDS system, at acceleration voltages of 5 kV. The thickness of the samples are measured by cross sectional SEM images. The electrical characterization of the solar cells were studied by light and dark current–voltage (I–V) using an Oriel solar simulator system with an AM1.5 G spectrum and 1 sun illumination. Capacitance-Voltage (C-V) were measured with an Agilent 4980A LCR-meter as a function of frequency varying from 10 kHz to 100 kHz and bias voltage from -2 V to 0.5 V, while AC voltage was 30 mV. Room temperature TRPL measurement were acquired by a Hamamatsu C12132. An area of 3 mm diameter of completed solar cells were illuminated by a 532 nm laser with 15 kHz repetition rate and 1.0 mW average power.

### 3. Results and discussion

#### 3.1 Morphological analysis

Top-view SEM images of CZTSe absorber layers with different thickness are shown in Fig.1.a to Fig.1.d and cross-sectional SEM images of devices with 700 nm and 1700 nm thickness are shown in Fig.1.e and Fig.1.f, respectively. SEM images reveal that by increasing the thickness the morphology of the absorbers improves, the grain size increases and less voids and pinholes can be observed in the films.

The composition of the samples was measured by EDS and the results are given in Table 1. Although the metallic ratios were kept constant in order to control the composition and X-ray fluorescence measurement of initial precursors confirmed the expected thicknesses for all samples, the Cu/Sn decreases constantly by decreasing the thickness. The reason of Sn excess composition of the thinner samples is not quite clear, however, the faster interdiffusion of the three metal layers and consequently reduced formation of volatile SnSe<sub>2</sub> might be the reason for larger amount of Sn in the thinner samples as compared to the thicker samples.

#### 3.2 Optical and electrical characterization:

Fig.2 (a) shows the room temperature photoluminescence (PL) of the solar cells. The position of the PL peak of the solar cells with different thickness is summarized in Table.2. By decreasing the thickness, the PL spectra become broader and the PL peak position shifts towards lower energies. The red shift is more significant for the thinner samples ( $\leq$  700 nm) and can be attributed to their composition variation (See. Fig.6.(a)). The PL peak of CZTSe is generally attributed to a donor to acceptor recombination in the presence of a large amount of band tail states and potential

fluctuations [5]. The Sn-rich composition of the thin samples can lead to the formation of  $Sn_{Cu}$  and  $Sn_{Zn}$  deep donors.

Fig.2 (b) shows the minority carrier lifetime,  $\tau$  of solar cells with different thickness. The minority carrier lifetime is derived using a two exponential fit to the photoluminescence decay curve. The slower decay time usually is considered as the minority carrier lifetime [6]. The minority carrier lifetime of the samples increases by increasing the thickness and it reaches 8.4 ns when thickness of absorber layer is 1700 nm. The enhancement of the minority carrier lifetime by increasing the thickness is correlated to the lower doping concentration (See. Fig.4). Also the Sn rich composition of ultra thin samples may lead to electron trapping defects such as Sn<sub>Cu</sub>, Sn<sub>Zn</sub> or other compensated defect clusters that increase the recombination and degrade the minority carrier lifetime significantly.

Fig.3 shows the illuminated / dark J-V curve (solid/dashed lines) of the champion solar cells of each thickness. The corresponding cell parameters are derived from the procedure explained by Hegedus and Shafarman [7] and are summarized in Table.2. Shunt resistance,  $R_{sh}$  is very low when the absorber thickness is  $\leq 1000$  nm and it improves significantly to  $512 \ \Omega.cm^2$  for the thickest sample since the film becomes more compact.  $J_{sc}$  is very low when the thickness of the device is  $\leq 1000$  nm because of the incomplete collection of solar spectrum. Further improvement of  $J_{sc}$  of samples thicker than 1000 nm can be attributed to a wider Space Charge Region (SCR) that facilitate the collection of carriers. Fig.6 (c) shows that by increasing the thickness from 1000 nm to 1700 nm the SCR increases from 70 nm to 300 nm and  $J_{sc}$  improves up to 36.4 mA/cm<sup>2</sup>. The significant improvement of  $V_{oc}$  by increasing the thickness indicates the reduction of recombination currents and it is consistent with the enhancement of minority carrier lifetime (See Fig.6 (b)). The recombination in CZTSe is mainly attributed to the recombination in SCR [8],

however, the dramatic decrease of  $V_{oc}$  in ultra thin samples might be also due to the contribution of rear interface recombination because of the decomposition of CZTSe near the Mo surface [9].

Fig.4 shows the doping density profile of absorbers with different thicknesses obtained by Mott– Schottky plot form the C-V measurement at frequency of 40 kHz. By increasing the thickness, the doping density at the edge of SCR, N<sub>a</sub>, decreases substantially, thus the SCR becomes wider. The reason for this large variation in doping density is not quite clear but might also be related to the large variation of the Cu to Sn ratio in the absorbers with different thickness. As Fig.6 (a) shows by increasing the thickness the Cu to Sn ratio increases while the doping density decreases significantly. Another possibility could be the contribution of elements that diffuse in from the SLG for example alkali elements. By decreasing the thickness the diffusion of these elements to the bulk and the p-n junction will be more detrimental.

Finally, the EQE measurement shown in Fig.5 indicates that by increasing the thickness photocurrent collection improves mainly due to the wider SCR and longer minority carrier lifetime.

### 4. Conclusions:

In conclusion, increasing the thickness of Sn/Zn/Cu precursor stacks improved the quality of CZTSe absorber layers prepared by selenization of e-beam evaporated precursors. Despite a similar composition in the starting layers, selenization of the thicker metal starting layers led to a larger Cu to Sn ratio in the final absorber, possibly because the thinner starting layers show faster interdiffusion of the metals and suppressed SnSe<sub>2</sub> evaporation. The enhanced physical quality of the absorber layers leads to higher performance of solar cells, especially due to a, longer minority carrier lifetime and accordingly higher  $V_{oc}$ . In addition, it was found that the doping of the absorber layer decreased with increasing the thickness and the wider space charge region of thicker devices lead to better collection of photogenerated carriers and higher  $J_{sc}$ .

## Acknowledgements

This project has received funding from the European Union's Horizon 2020 research and innovation programme under grant agreement No 640868. This research is partially funded by the Flemish government, Department Economy, Science and innovation. This work is also funded by FEDER funds through the COMPETE 2020 Programme and National Funds through FCT - Portuguese Foundation for Science and Technology under the project UID/CTM/50025/2013. Samaneh Ranjbar acknowledges the financial support of the Portuguese Science and Technology Foundation (FCT) through PhD grant SFRH / BD / 78409 / 2011.

#### References

- S. Delbos, K<sup>°</sup>esterite thin films for photovoltaics: a review, EPJ Photovolt. 3 (2012) 35004-35016.
- W. Wang, M.T. Winkler, O. Gunawan, T. Gokmen, T.K. Todorov, Y. Zhu, D.B. Mitzi, Device characteristics of CZTSSe thin-film solar cells with 12.6% efficiency, Adv. Energy Mater. 4 (2014) 1301465–1301469.
- [3] Y. Ren, J.J. Scragg, C. Frisk, J. K. Larsen, S.Y. Li, and C. Platzer-Björkman, Influence of the Cu<sub>2</sub>ZnSnS<sub>4</sub> absorber thickness on thin film solar cells, Phys. Status Solidi A 212, (2015) 2889–2896.
- [4] G. Brammertz, M. Buffière, S. Oueslati, H. ElAnzeery, K. Ben Messaoud, S. Sahayaraj, C.
   Köble, M. Meuris, and J. Poortmans, Characterization of defects in 9.7% efficient
   Cu<sub>2</sub>ZnSnSe<sub>4</sub>-CdS-ZnO solar cells, Appl. Phys. Lett. 103 (2013) 163904-163907.

- [5] S. Oueslati, G. Brammertz, M. Buffière, C. Köble, T. Oualid, M. Meuris and J. Poortmans, Photoluminescence study and observation of unusual optical transitions in Cu<sub>2</sub>ZnSnSe<sub>4</sub>/CdS/ZnO solar cells, Sol. Energy mater. and Sol. Cells, 134 (2015) 340-345.
- [6] A. Kanevce, D. H. Levi and D. Kuciauskas, The role of drift, diffusion, and recombination in time resolved photoluminescence of CdTe solar cells determined through numerical simulation, Prog. Photovolt: Res. Appl. 22, (2014) 1138–1146.
- [7] S. S. Hegedus and W. N. Shafarman, Thin-film solar cells: device measurements and analysis. Prog. Photovolt: Res. Appl. 12 (2004) 155–176.
- [8] G. Brammertz, S. Oueslati, M. Buffiere, J. Bekaert, H. El Anzeery, K. B. Messaoud, S. Sahayaraj, T. Nuytten, C. K<sup>o</sup>oble, M. Meuris, and J. Poortmans, Investigation of Properties Limiting Efficiency in Cu<sub>2</sub>ZnSnSe<sub>4</sub>-Based Solar Cells, IEEE J. of photovolt. 5 (2015) 649-655.
- [9] J.J. Scragg, J.T. Wätjen, M. Edoff, T. Ericson, T. Kubart, C. Platzer-Björkman, A Detrimental Reaction at the Molybdenum Back Contact in Cu<sub>2</sub>ZnSn(S,Se)<sub>4</sub> Thin-Film Solar Cells, J. of the American Chemical Society, 134 (2012) 19330-19333.

## List of figure captions:

## List of table captions:

 Table 1. Metal composition of CZTSe absorbers with different thickness.

Table 2. Electrical and optical parameters of solar cells with different absorber thickness: short circuit current ( $J_{sc}$ ), open circuit voltage ( $V_{oc}$ ), fill factor (FF), efficiency ( $\eta$ ), shunt resistance ( $R_{sh}$ )

and series resistance  $(R_s)$  are derived from illuminated current-voltage (J-V) measurement,  $J_{sc}$  (EQE) are derived from external quantum efficiency (EQE). PL peak position (PL) is derived form photoluminescence measurement.

Thickness (nm)	Thickness (nm)	Cu	Cu	Zn	Cu	
Sn/Zn/Cu	After Selenization	Zn	Sn	Sn	Sn+Zn	
54/26/30	300	1.97	1.24	0.63	0.76	
107/53/60	730	1.34	1.38	1.03	0.68	
215/105/120	1000	1.51	1.59	1.06	0.77	
260/126/145	1200	1.49	1.59	1.07	0.77	
310/150/160	1700	1.71	1.74	1.04	0.86	

Table 1. Metal composition of CZTSe absorbers with different thickness.

Table 2. Electrical and optical parameters of solar cells with different absorber thickness: short circuit current ( $J_{sc}$ ), open circuit voltage ( $V_{oc}$ ), fill factor (FF), efficiency ( $\eta$ ), shunt resistance ( $R_{sh}$ ) and series resistance ( $R_s$ ) are derived from illuminated current-voltage (J-V) measurement,  $J_{sc}$  (EQE) are derived from external quantum efficiency (EQE). PL peak position (PL) is derived form photoluminescence measurement.

Thickness (nm)	J <sub>sc</sub> (mA/cm <sup>2</sup> )	J <sub>sc</sub> (EQE) (mA/cm <sup>2</sup> )	Voc (mV)	FF (%)	η (%)	R <sub>sh</sub> (Ω.cm <sup>2</sup> )	Rs (Ω.cm <sup>2</sup> )	PL (eV)
300	2.3	_	175.0	25	0.1	68	2.07	0.89
730	15.2	_	262.0	34	1.4	31	1.16	0.89
1000	26.9	26.60	363.0	47	4.6	98	1	0.93
1200	30	34.92	385.0	54	6.2	277	1.26	0.91
1700	36.4	39.50	406.0	53	7.8	512	1.35	0.95

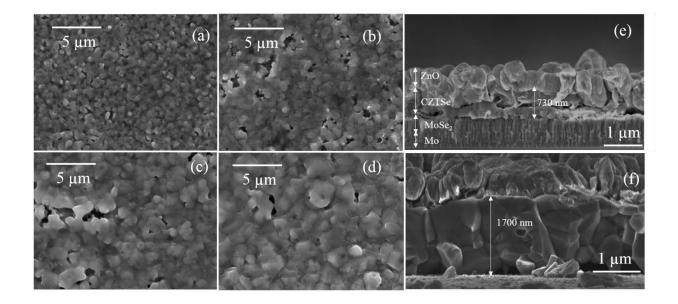


Fig.1. Top view SEM images of absorber layers: (a) to (d) absorbers with 300, 700, 1200,1700 nm thickness, respectively. (e) and (f) Cross section SEM images of solar cells with absorber layer thickness of 700 nm and 1700 nm.

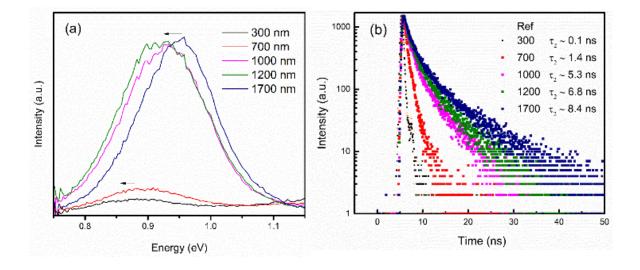


Fig.2. (a) Photoluminescence spectra and (b) time resolved Photoluminescence spectra of solar cells with different absorber thickness. Minority carrier lifetime ( $\tau$ ) is derived form a two

exponencial fit.

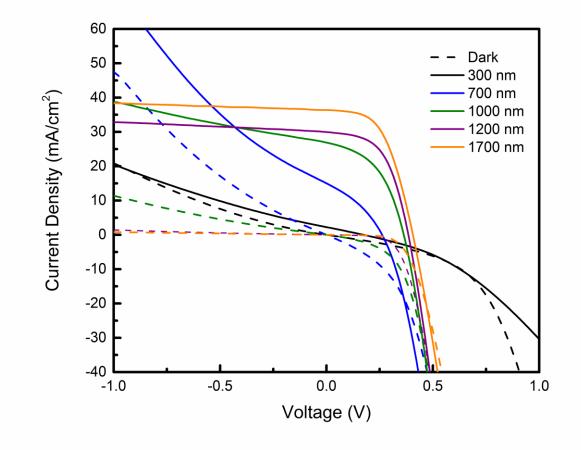


Fig.3. Current-Voltage measurement of solar cells with different absorber thickness under dark (dashed line) and 1 sun illumination (solid line).

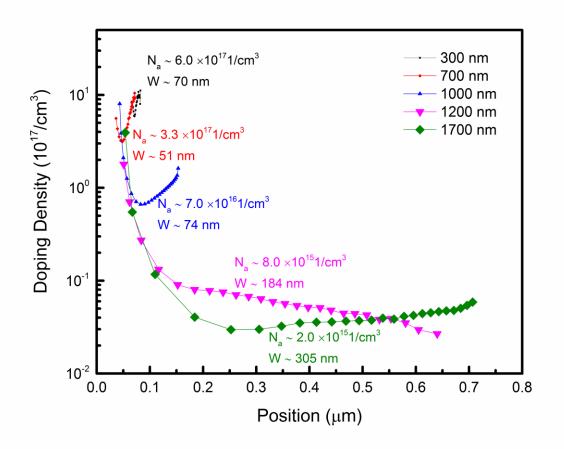


Fig.4. Doping density profile of solar cells with different absorber thickness. The hole concentaration (N<sub>a</sub>) and space charge region width (W) are drived from Mott–Schottky polt.

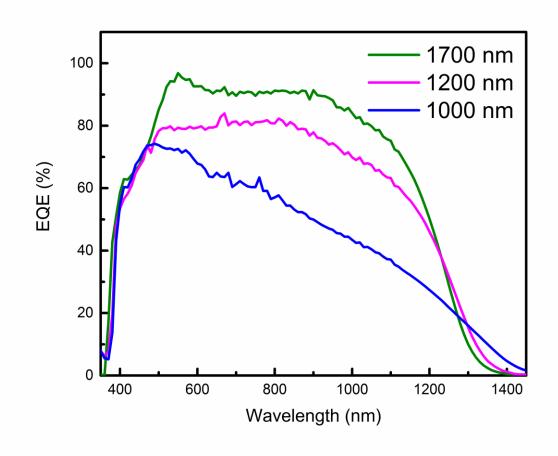


Fig.5. External quantum efficiency (EQE) of solar cells with different absorber layer thickness.

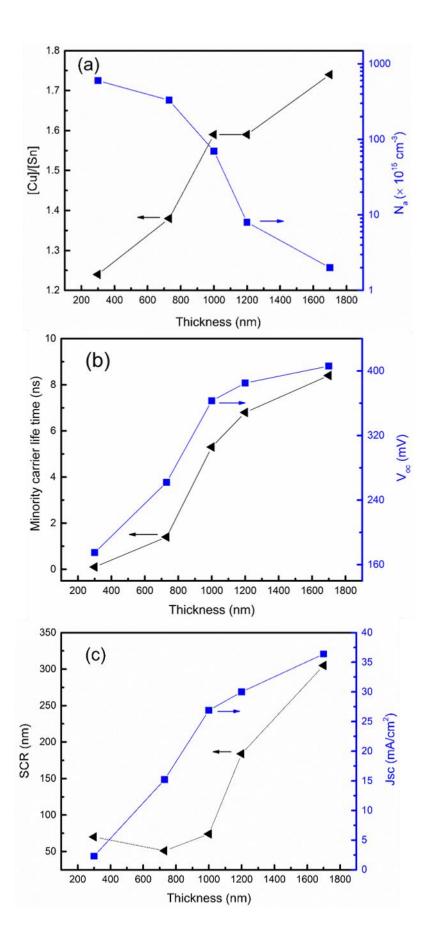


Fig.6. (a) Cu to Sn ratio and hole concentration ( $N_a$ ), (b) Minority carrier lifetime and  $V_{oc}$ , (c) Depletion width (SCR) and  $J_{sc}$  at various thickness.